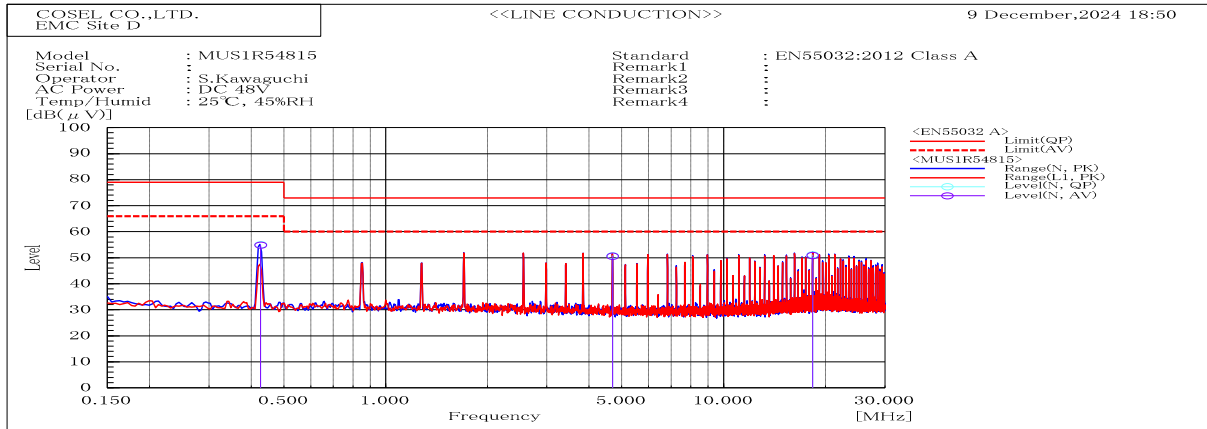
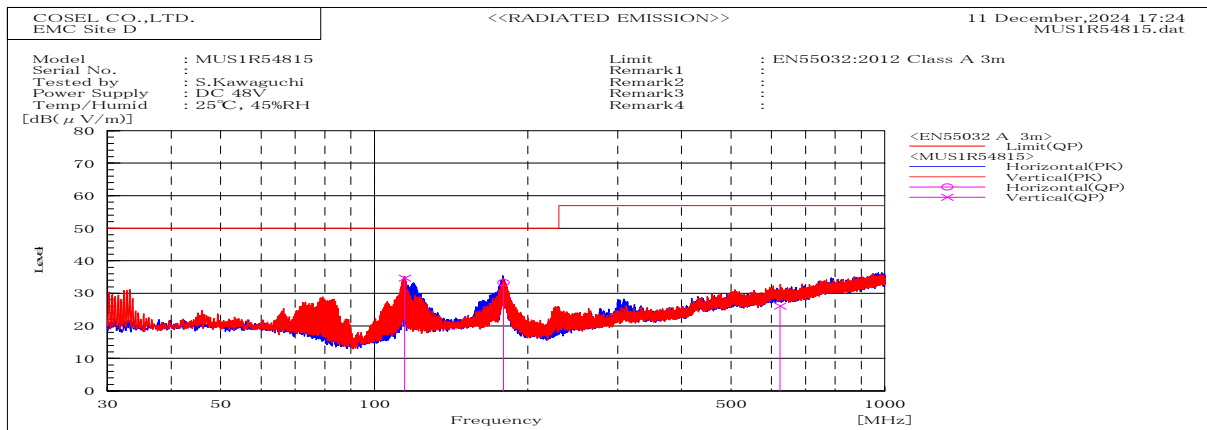


DATA SHEET

Model		MUS1R54815	Date	05-Mar-25
Test		EMI Line conduction & Radiated emission	Temp.	25 degreeC
			Humid.	45 %RH
			Tested by	S.Kawaguchi



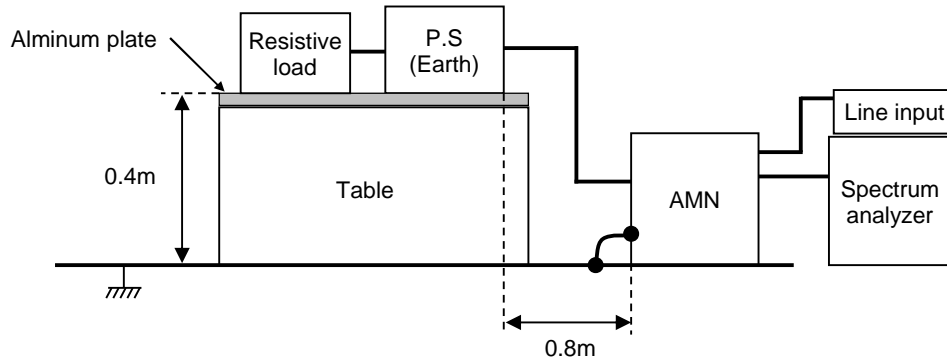
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
4.694	N	50.7	50.6	73	60	22.3	9.4	Pass	
18.349	N	51.2	50.9	73	60	21.8	9.1	Pass	
0.427	N	55	54.9	79	66	24	11.1	Pass	



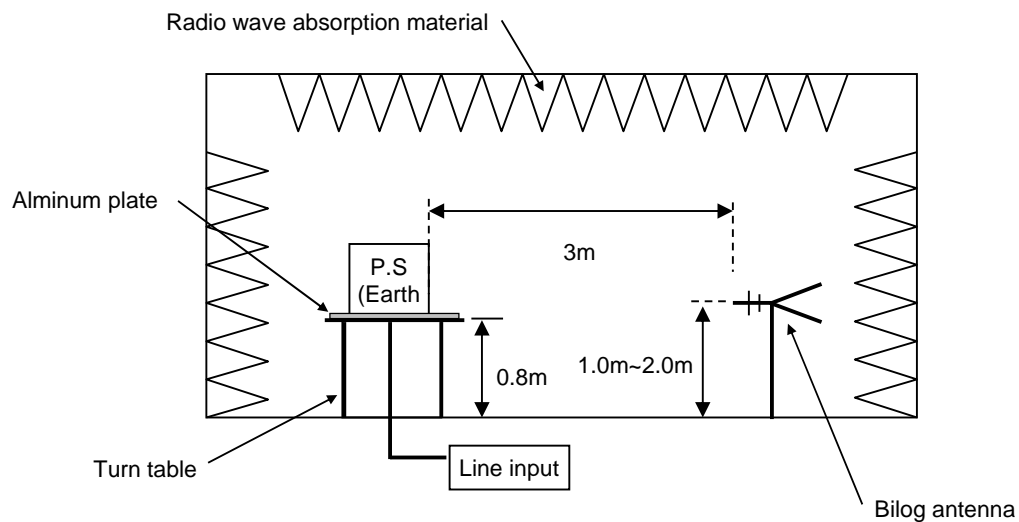
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP						
114.692	V	Stable	34.7	50	15.3	Pass	101.6	295		
179.064	H	Stable	33.3	50	16.7	Pass	198.3	226.3		
624.196	V	Stable	26.1	57	30.9	Pass	100.2	331.6		

DATA SHEET		Date	05-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

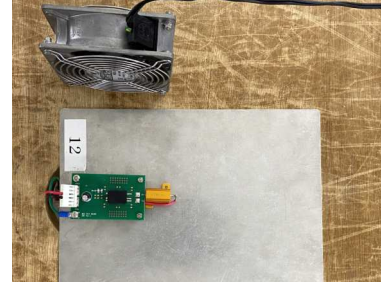
Test : EMI
Model Name: MUS1R5□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

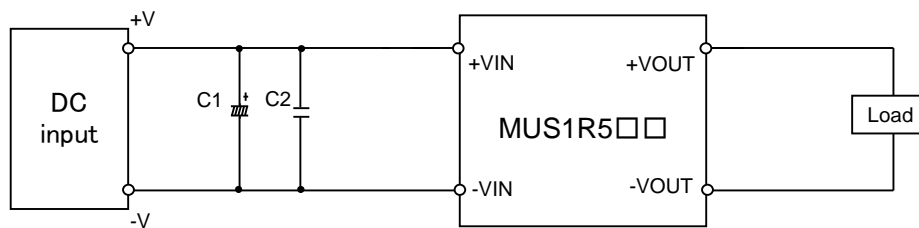


Fig.1 MUS1R505□, MUS1R512□, MUS1R524□ Testing circuitry

C1 :	MUS1R505□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUS1R512□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS1R524□	-	
C2 :	MUS1R505□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS1R512□	25V 22 μ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS1R524□	50V 10 μ F	Ceramic capacitor (C3216X7R1H106KT TDK)

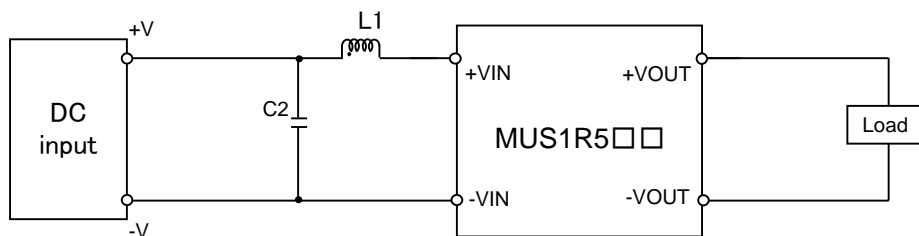


Fig.2 MUS1R548□ Testing circuitry

C2 :	MUS1R548□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS1R548□	520mA 15 μ H	Inductor (LQH32PN150MN0L MURATA MANUFACTURING)